Search	Notes	

Application/Contr	ol No.	Applicant(s) Reexaminat	/Patent under ion
10/829,268		MOMIYAMA	A, FUJIO
Examiner		Art Unit	
Tiffany L. Webb	_	3616	

	SEAR	CHED	
Class	Subclass	Date	Examiner
280	124.157	3/15/2006	TLW
280	782	3/15/2006	TLW
	783	3/15/2006	TLW
301	124.1	3/15/2006	tlw

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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		2071.44	

DATE 3/15/2006 3/16/2006	TLW TLW
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